

## MIC5821/5822

#### 8-Bit Serial-Input Latched Drivers

### **General Description**

BiCMOS technology gives the MIC5821/5822 family flexibility beyond the reach of standard logic buffers and power driver arrays. These devices each have an eight-bit CMOS shift register, CMOS control circuitry, eight CMOS data latches, and eight bipolar current-sink Darlington output drivers. The 500mA outputs are suitable for use with incandescent bulbs and other moderate to high current loads. The drivers can be operated with a split supply where the negative supply is down to –20V. Except for maximum driver output voltage ratings, the MIC5821 and MIC5822 are identical.

These devices have greatly improved data-input rates. With a 5V logic supply they will typically operate faster than 5 MHz. With a 12V supply significantly higher speeds are obtained. The CMOS inputs are compatible with standard CMOS, PMOS, and NMOS logic levels. TTL and DTL circuits may require the use of appropriate pull-up resistors. By using the serial data output, the drivers can be cascaded for interface applications requiring additional drive lines.

#### **Features**

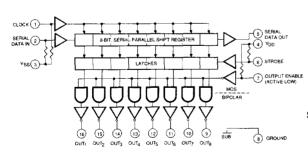
- · 3.3 MHz Minimum Data-Input Rate
- · CMOS, PMOS, NMOS, TTL Compatible
- Internal Pull-Down or Pull-Up Resistors
- Low-Power CMOS Logic and Latches
  High-Voltage Current-Sink Outputs
- Single or Split Supply Operation

### **Ordering Information**

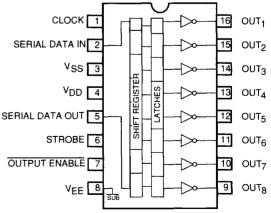
Part Number	Temperature Range	Package
MIC5821CN*	0°C to +70°C	16-Pin Plastic DIP
MIC5821BN	–40°C to +85°C	16-Pin Plastic DIP
MIC5822BN	-40°C to +85°C	16-Pin Plastic DIP
MIC5822AJ	–55°C to +125°C	16-Pin Ceramic DIP
5962-8764101EA <sup>†</sup>	-55°C to +125°C	16-Pin Ceramic DIP

Micrel reserves the right to substitute MIC5821BN grade devices for the MIC5821CN

## **Functional Diagram**



## Pin Configuration

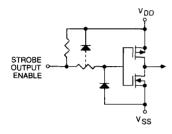


(Plastic and Ceramic DIP)

7-37

<sup>†</sup> Standard Military Drawing number for MIC5822AJBQ

## **Typical Input Circuits**



## **Absolute Maximum Ratings (Note 1)**

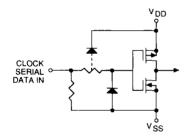
at 25°C Free-Air Temperature and V<sub>SS</sub> = 0V

Output Voltage, V <sub>CE</sub>	(MIC5821)	50\	1
	(MIC5822)	80\	1
Output Voltage, V <sub>CE SUS</sub>			/
	(MIC5822)(No	ote 3) 50\	/
Logic Supply Voltage, VDI	)	15\	/
Input Voltage Range, VIN	-0.	3V to V <sub>DD</sub> + 0.3\	/
V <sub>DD</sub> – V <sub>EE</sub>		25\	/
Emitter Supply Voltage, V <sub>I</sub>	ΞE	-20\	/
Continuous Output Curren		500m <i>A</i>	١
Package Power Dissipatio	n, PD( Note 1)	1.67W	ı
Operating Temperature Ra	ange, T <sub>A</sub>	-55°C to +125°C	)
Storage Temperature Ran	ge, T <sub>S</sub>	-65°C to +150°C	)

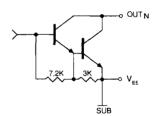
Note 1: Derate at the rate of 16.7mW/°C above  $T_A = 25$ °C (Plastic DIP).

Note 2: CMOS devices have input static protection but are susceptible to damage when exposed to extremely high static electrical charges.

Note 3: For inductive load applications.



## **Typical Output Driver**



## Maximum Allowable Duty Cycle (Plastic DIP)

Number of Outputs ON (I <sub>OUT</sub> = 200mA	Maximum Allowable Duty Cycle at Ambient Temperature of										
V <sub>DD</sub> = 12V)	25°C	40°C	50°C	60°C	70°C						
8	73%	62%	55%	47%	40%						
7	83%	71%	62%	54%	46%						
6	97%	82%	72%	63%	53%						
5	100%	98%	87%	75%	63%						
4	100%	100%	100%	93%	79%						
3	100%	100%	100%	100%	100%						
2	100%	100%	100%	100%	100%						
1	100%	100%	100%	100%	100%						

## 7

# **Electrical Characteristics** at $T_A = 25^{\circ}C V_{DD} = 5V$ , $V_{EE} = V_{SS} = 0V$ (unless otherwise specified)

		Applicable		Limits				
Characteristic	Symbol	Devices	Test Conditions	Min.	Max.	Unit		
Output Leakage Current	ICEX	MIC5821	V <sub>OUT</sub> = 50V		50	μΑ		
			V <sub>OUT</sub> = 50V, T <sub>A</sub> = +70°C		100	]		
	ļ	MIC5822	V <sub>OUT</sub> = 80V		50	1		
***			V <sub>OUT</sub> = 80V, T <sub>A</sub> = +70°C		100			
Collector-Emitter	V <sub>CE(SAT)</sub>	Both	I <sub>OUT</sub> = 100mA		1.1	V		
Saturation Voltage			I <sub>OUT</sub> = 200mA		1.3	]		
			$I_{OUT} = 350 \text{mA}, V_{DD} = 7.0 \text{V}$		1.6	<u> </u>		
Input Voltage	V <sub>IN(0)</sub>	Both			0.8	V		
	V <sub>IN(1)</sub>	Both	$V_{DD} = 12V$	10.5				
	Ì		V <sub>DD</sub> = 10V	8.5				
			V <sub>DD</sub> = 5.0V	3.5				
Input Resistance	R <sub>IN</sub>	Both	V <sub>DD</sub> = 12V	50		kΩ		
			V <sub>DD</sub> = 10V	50				
			V <sub>DD</sub> = 5.0V	50		]		
Supply Current	I <sub>DD(ON)</sub>	Both	One Driver ON, V <sub>DD</sub> = 12V		4.5	mA		
			One Driver ON, V <sub>DD</sub> = 10V		3.9	]		
			One Driver ON, V <sub>DD</sub> = 5.0V		2.4			
			All Drivers ON, V <sub>DD</sub> = 12V		16			
			All Drivers ON, V <sub>DD</sub> = 10V		14			
			All Drivers ON, V <sub>DD</sub> = 5.0V		8	]		
	I <sub>DD(OFF)</sub>	Both	All Drivers OFF, V <sub>DD</sub> = 5.0V, All Inputs = 0V		1.6			
			All Drivers OFF, V <sub>DD</sub> = 12V, All Inputs= 0V		2.9			

# $\textbf{Electrical Characteristics} \quad \text{MIC5822AJ/AJB at T}_{A} = -55^{\circ}\text{C}, \ V_{DD} = 5\text{V}, \ V_{SS} = V_{EE} = 0\text{V} \ (\text{unless otherwise noted})$

			Limits				
Characteristic	Symbol	Test Conditions	Min.	Max.	Unit		
Output Leakage Current	ICEX	V <sub>OUT</sub> = 80V		50	μА		
Collector-Emitter	V <sub>CE(SAT)</sub>	I <sub>OUT</sub> = 100mA		1.3	٧		
Saturation Voltage	' '	I <sub>OUT</sub> = 200mA		1.5			
		I <sub>OUT</sub> = 350mA, V <sub>DD</sub> = 7.0V		1.8	1		
Input Voltage	V <sub>INO)</sub>			0.8	V		
	V <sub>IN(1)</sub>	V <sub>DD</sub> = 12V	10.5		1		
	\ '	V <sub>DD</sub> = 5.0V	3.5		1		
Input Resistance	RIN	V <sub>DD</sub> = 12V	35		kΩ		
		V <sub>DD</sub> = 10V	35		1		
		V <sub>DD</sub> = 5.0V	35		1		
Supply Current	I <sub>DD(ON)</sub>	One Driver ON, V <sub>DD</sub> = 12V		5.5	mA		
	, ,	One Driver ON, V <sub>DD</sub> = 10V		4.5	1		
		One Driver ON, V <sub>DD</sub> = 5.0V		3.0	1		
		All Drivers ON, V <sub>DD</sub> = 12V		16	1		
		All Drivers ON, V <sub>DD</sub> = 10V		14	1		
		All Drivers ON, V <sub>DD</sub> = 5.0V		10	1		
	I <sub>DD(OFF)</sub>	All Drivers OFF, V <sub>DD</sub> = 12V		3.5	1		
	,,	All Drivers OFF, V <sub>DD</sub> = 5.0V		2.0	1		

1997 7-39

**Electrical Characteristics** MIC5822AJ/AJB at  $T_A = +125^{\circ}C$ ,  $V_{DD} = 5V$ ,  $V_{SS} = V_{EE} = 0V$  (unless otherwise noted)

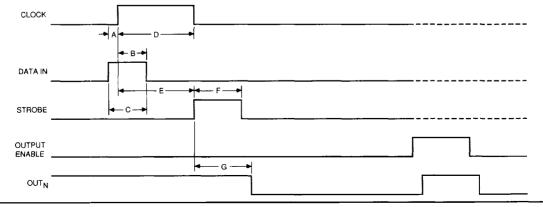
			Limits				
Characteristic	Symbol	Test Conditions	Min.	Max.	Unit		
Output Leakage Current	ICEX	V <sub>OUT</sub> = 80V		500	μА		
Collector-Emitter	V <sub>CE(SAT)</sub>	l <sub>OUT</sub> = 100mA		1.3	V		
Saturation Voltage		I <sub>OUT</sub> = 200mA		1.5	1		
		I <sub>OUT</sub> = 350mA, V <sub>DD</sub> = 7.0V		1.8	1		
Input Voltage	V <sub>IN(0)</sub>			0.8	V		
	V <sub>IN(1)</sub>	V <sub>DD</sub> = 12V	10.5		1		
		V <sub>DD</sub> = 5.0V	3.5		1		
Input Resistance	R <sub>IN</sub>	V <sub>DD</sub> = 12V	50		kΩ		
		V <sub>DD</sub> ≈ 10V	50		1		
		V <sub>DD</sub> ≈ 5.0V	50		1		
Supply Current	I <sub>DD(ON)</sub>	One Driver ON, V <sub>DD</sub> = 12V		4.5	mA		
		One Driver ON, V <sub>DD</sub> = 10V		3.9	1		
		One Driver ON, V <sub>DD</sub> = 5.0V		2.4	1		
		All Drivers ON, V <sub>DD</sub> = 12V		16	1		
		All Drivers ON, V <sub>DD</sub> = 10V		14	1		
		All Drivers ON, V <sub>DD</sub> = 5.0V		8	7		
	IDD(OFF)	All Drivers OFF, V <sub>DD</sub> = 12V		2.9	1		
		All Drivers OFF, V <sub>DD</sub> = 5.0V		1.6	1		

## MIC5821/5822 Family Truth Table

Serial		Shi	ft Reg	jister	Conte	ents	Serial		L	.atch	Cont	ents				Output Conten			
Data Input	Clock Input	l <sub>1</sub>	l <sub>2</sub>	l <sub>3</sub>		l <sub>8</sub>	Data Output	Strobe Input	l <sub>1</sub>	l <sub>2</sub>	l <sub>3</sub>		18	Output Enable	l <sub>1</sub>	 l <sub>2</sub>	l <sub>3</sub>		l <sub>8</sub>
Н		Н	R <sub>1</sub>	R <sub>2</sub>		R <sub>7</sub>	R <sub>7</sub>												
L		L	R <sub>1</sub>	R <sub>2</sub>		R <sub>7</sub>	R <sub>7</sub>							ļ					
Х		R <sub>1</sub>	R <sub>2</sub>	R <sub>3</sub>		R <sub>8</sub>	R <sub>8</sub>	1											
		Х	Х	Х		Х	X	L	R <sub>1</sub>	R <sub>2</sub>	Rз		R <sub>8</sub>						
		P <sub>1</sub>	P <sub>2</sub>	P <sub>3</sub>		P <sub>8</sub>	P <sub>8</sub>	Н	P1	P <sub>2</sub>	P <sub>3</sub>		P <sub>8</sub>	L	P <sub>1</sub>	P <sub>2</sub>	Рз		P <sub>8</sub>
									X	Х	Х		Χ	Н	Н	Н	Н		Н

L = Low Logic Level H = High Logic Level X = Irrelevant P = Present State R = Previous State

## **Timing Diagram**



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### **Timing Conditions**

(TA = +25°C, Logic Levels are VDD and Vss)

		$V_{DD} = 5.0V$
A.	Minimum Data Active Time Before Clock Pulse (Data Set-Up Time)	75 ns
B.	Minimum Data Active Time After Clock Pulse (Data Hold Time)	75 ns
C.	Minimum Data Pulse Width	150 ns
D.	Minimum Clock Pulse Width	150 ns
E.	Minimum Time Between Clock Activation and Strobe	300 ns
F.	Minimum Strobe Pulse Width	100 ns
G.	Typical Time Between Strobe Activation and Output Transition	500 ns

SERIAL DATA present at the input is transferred to the shift register on the logic "0" to logic "1" transition of the CLOCK input pulse. On succeeding CLOCK pulses, the registers shift data information towards the SERIAL DATA OUTPUT. The SERIAL DATA must appear at the input prior to the rising edge of the CLOCK input waveform.

Information present at any register is transferred to its respective latch when the STROBE is high (serial-to-parallel conversion). The latches will continue to accept new data as long as the STROBE is held high. Applications where the latches are bypassed (STROBE tied high) will require that the ENABLE input be high during serial entry.

When the ENABLE input is high, all of the output buffers are disabled (OFF) without affecting the information stored in the latches or shift register. With the ENABLE input low, the outputs are controlled by the state of the latches.

### **Typical Applications**

#### MIC5822 Level Shifting Lamp Driver with Darlington Emitters Tied to a Negative Supply

